## Notice of References Cited Application/Control No. 10/598,491 Examiner JOSEPH DEAN, JR Applicant(s)/Patent Under Reexamination OYAMA ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-2002/0034939	03-2002	Wenzel, Peter	455/426	
*	В	US-2005/0058100	03-2005	Lee et al.	370/331	
*	C	US-2004/0023653	02-2004	O'Neill, Alan	455/432.1	
*	D	US-2004/0100951	05-2004	O'neill, Alan	370/389	
	Е	US-				
	F	US-				
	G	US-				
	Н	US-				
	I	US-				
	J	US-				
	K	US-				
	L	US-				
	М	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.